Application of the PCB-Embedding Technology in Power Electronics State of the Art and Proposed Development

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Introduction

State of the Art of PCB embedding

Proposition – Design Tools for Power Electronics

Conclusions



Introduction

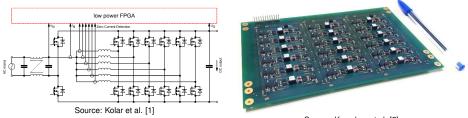
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Power electronics – Areas for Progress

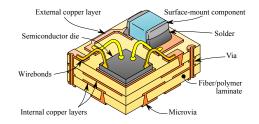




- Excellent active devices are now available (SiC, GaN)
- Many topologies introduced over the years;
 - Recent changes: multicellular structures
- Integration and Packaging are the main areas for progress
 - Reduce size and circuit parasitics, improve thermal management...
 - Manage incresed interconnexion density



PCB Technology



Printed Circuit Board is

- Mature

 Large range of available design software
 - Can be manufactured in large quantities, low price
 - Mainly oriented towards microelectronics and low power
- Flexible ► Custom design
 - Many configurations possible
- Limited
 Poor thermal conductivity



Introduction

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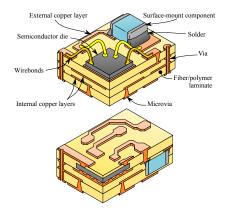
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Why Embedding?

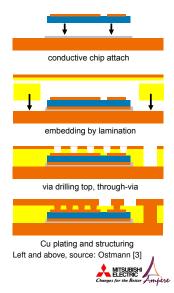
- Optimize thermal management
 - Heat sources closer to heatsink
 - Dual side cooling
- Improve performance
 - Shorter interconnects
 - Lower inductances
- Reduce size
 - Use substrate volume
- Manage complex interconnects
 - Batch process





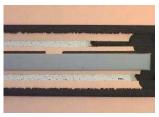
- Most embedding effort on power dies:
 - Most power density
 - Fastest voltage/current transients
- Requires special finish on dies
 - 5-10 µm Cu (not standard)
 - Buffer for UV laser
 - Also for microetch in plating step
- Backside connexion by sintering or vias
 - Sintering compatible with standard die
 Vias require Cu finish and adhesive

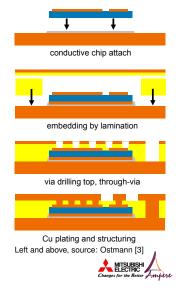




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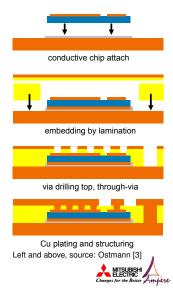






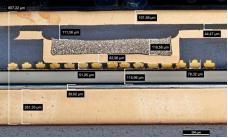
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Some alternative techniques

- Stud bumps and machining
- Foam interposer
- Mechanical drilling



Source: Hoene et al. [4]



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Mechanical drilling



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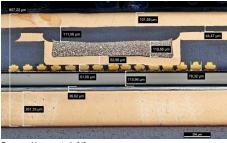


Source: Pascal et al. [5]



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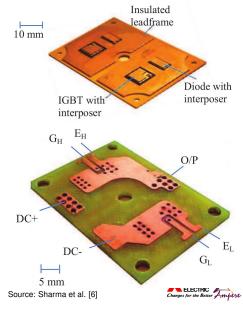
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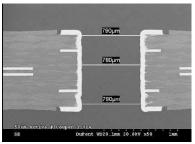
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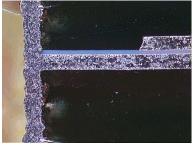
Source: Pascal et al. [5]



Embedding of Formed Components – Capacitors



Source: Dupont [7]



Source: Andresakis [8]

- introduction of a capacitive layer in the stack-up
 - ► thin layer (8–25 µm)
 - ▶ high permittivity (e.g. BaTiO₃ filler)
- single layer plane capacitor
- → low capacitance density
- → limited voltage strength
 - ► \approx 1 nF cm⁻² for 100 V rating
- more suited to GHz-range decoupling than to power electronics



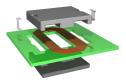
Embedding of Formed Components – Inductors

Magnetic Layer

- ► Relies on magnetic/polymer film → Low μ_r
- Limited to 10 100 W



Source: Waffenschmidt et al. [9]

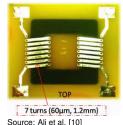


Planar magnetic components

- Very common, but not really embedded
- High performance
- Compatible with low (W) or high power (kW)

Embedded core

- Strong industrial development (Murata, AT&S, Würth)
- Currently limited to low power (W)



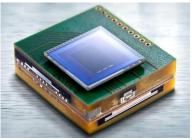
Embedding of Inserted Components

Soldered components:

- Suits most Surface-Mount Devices
- Connexions with regular vias

Vias to components:

- Requires components with Cu finish
- More compact (vias on components)



Source: Ostmann [3]



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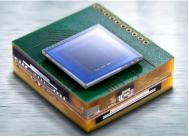
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For power electronics

- Embedding of "large" capacitors (1 µF range)
- Embedding of gate driver ICs and peripheral components, control



Source: Ostmann [3]



Thermal Management of Embedded Components - 1

- Poor thermal conductivity of FR4 compared to ceramics (1-7 W m⁻¹ K⁻¹ vs 150 W m⁻¹ K⁻¹ for AIN)
- ▶ In theory better breakdown field (\approx 50 kV mm⁻¹ vs. 20 kV mm⁻¹)

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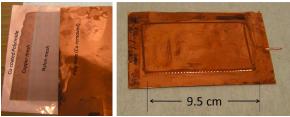
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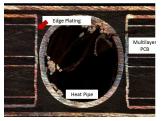
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► Micro-vias (electrically conductive), Filled cores (e.g. alumina)

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- To improve through-plane heat conduction:
 - ► Micro-vias (electrically conductive), Filled cores (e.g. alumina)
- To increase in-plane heat conduction:
 - Thicker copper, Anisotropic layers (Graphite), Dual-phase





Source: left: Liew et al. [11]; right: Silvano et al. [12]

- Temperature-related issues
 - Rapid degradation above 190 °C
 - Hydrocarbon, polyimide-based PCBs resistant up to 250 °C

Thermal cycling issues

 CTE of PCBs much higher than ceramic or semiconductor
 Availability of low-CTE materials

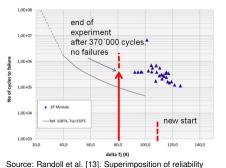
Other PCB-specific issues

moisture absorption,

conductive anodic filaments.

→ No showstopper identified yet!





power modules

data for dies in PCB on Infineon's results for standard

Source: Perrin et al. [14]. Left: standard FR4, right: low-CTE. Magnetic core embedded, after 1000 thermal cycles (-50/200 °C) Temperature-related issues

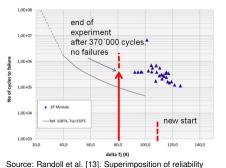
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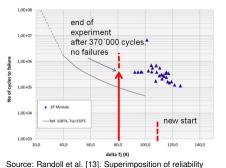
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Conclusions on Embedding Technology

Application to Power Electronics

- Many components can be embedded
 - Dies require Cu finish
 - Large components?
- Acceptable thermal performance



SiC PFC Cell, 750 W, PCB size $7 \times 7 \times 1$ cm³. SiC dies, gate driver circuit, PFC inductor and temperature sensors embedded in PCB.



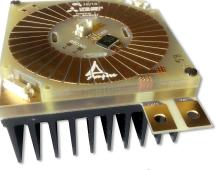
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Open questions

- ► Find the sweet spot:
 - Embedding power dies only?
 - Embed everything?
 - Or somewhere in-between?
 - Are flat converters desirable?
- How to design for embedding?



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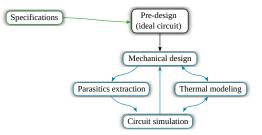




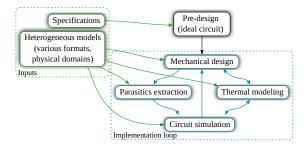
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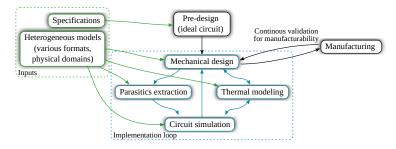




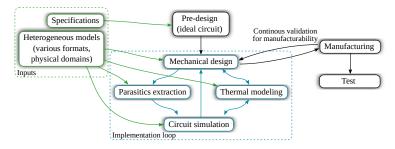




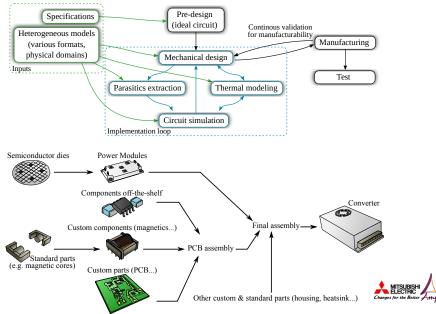




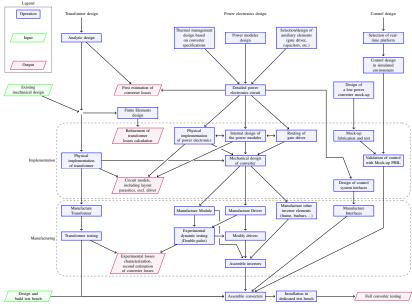






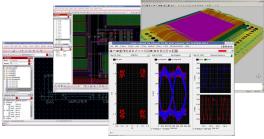


Design in Power Electronics - Real-case example



Source: Supergrid Institute, submitted article

Design in Microelectronics

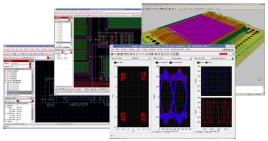


Integrated software for

- Circuit design
- Routing
- Simulation
- Mask generation...

Source: Cadence

Design in Microelectronics



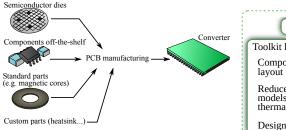
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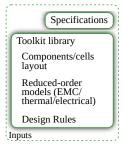
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Why is it not available in power electronics?

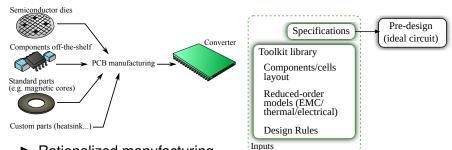
- powerful financial incentive for virtual prototyping
 - ► A 45 nm mask set costs ≈ 2 M\$ (source: Electronic design, 2009)
- Limited technology variations
 - Most of the circuit is monolithic
 - No flexibility allowed in technology configuration
 - Manufacturers supply a "design toolkit" describing the technology



- Rationalized manufacturing
- → Reduce design variability
- Design Toolkit for simulation and validation
- → Design for manufacturing

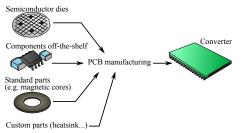




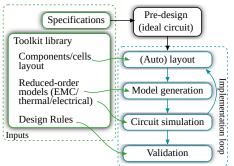


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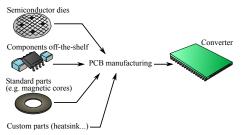




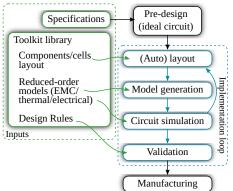
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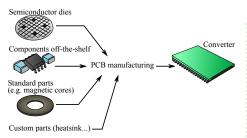




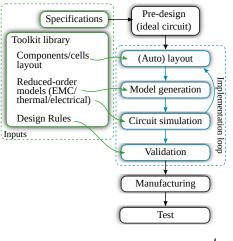
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20/28

- ► Fully custom designs, as opposed to modular
- Automatic Design for Manufacturing (fabless approach)
- Single, well controlled technology:
 Qualification: of technology rather than products
 Scalability: same technology for test and production runs
 Prototyping: share panels across projects
- ➔ Basically all the usual features in IC design.
- Reduced choice of components
 - Must be in the toolkit library
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- Large choice of existing software (PCB layout, circuit simulators, EM modeling)
- Need to identify suitable modelling approach (speed/accuracy trade-off)
- Software "glue" required for automatic model generation
- Define design rules for PCB embedding

Required for automatic design validation

Long experimental work required.

The impact on the supply chain must also be assessed



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Conclusions – Exploiting the PCB Embedding

- PCB embedding is very promising
 - Provides a single, unified techology for power electronics (W to 10's of kW range)
 - High performance
 - Scalable, reasonable cost...
- Situation comparable to microelec. in the 70's
 - Many technologies available, but no standard
 - No separation between design and manuf.
 - ➔ Need for Design Rules and uniformization
- Large effort required on the design tools
 - Allow Design for Manufacturing
 - Objective: efficient virtual prototyping





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